



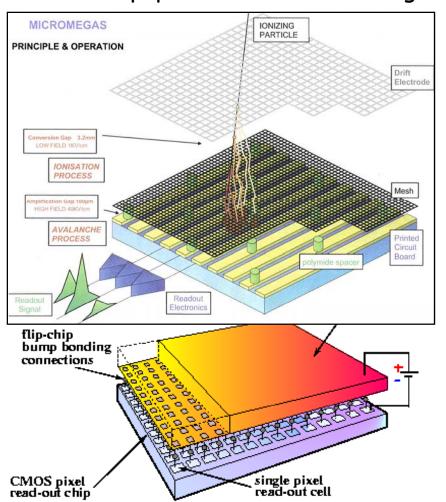
# Update on Silicon Pixel Readout for a TPC at NIKHEF

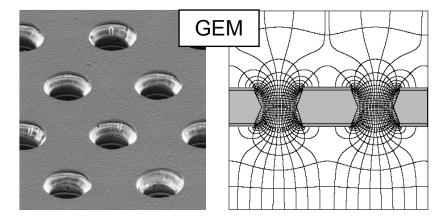
TILC08 - Sendai 4 March 2008

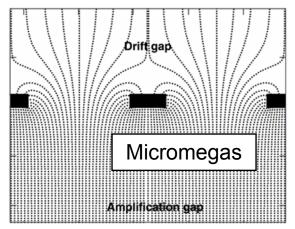
> Jan Timmermans NIKHEF

## Micro Patterned Gaseous Detectors

- High field created by Gas Gain Grids
- · Most popular: GEM & Micromegas





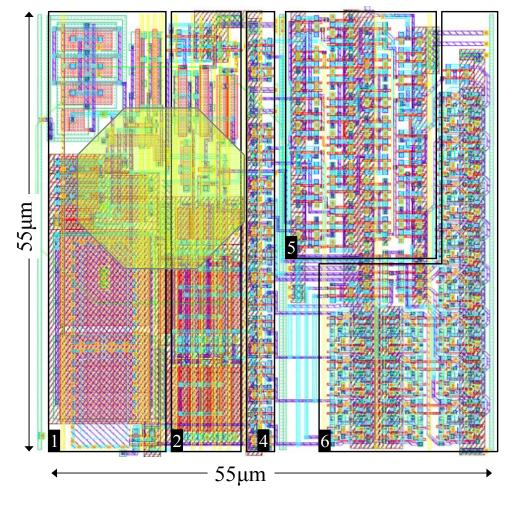


Use 'naked' CMOS pixel readout chip as anode



CERN

#### Timepix pixel



Timepix chip:

•256x256 pixels

•pixel: 55x55 µm<sup>2</sup>

•active surface:

14x14 mm<sup>2</sup>

Timepix chip (1st version) produced Sept. 2006

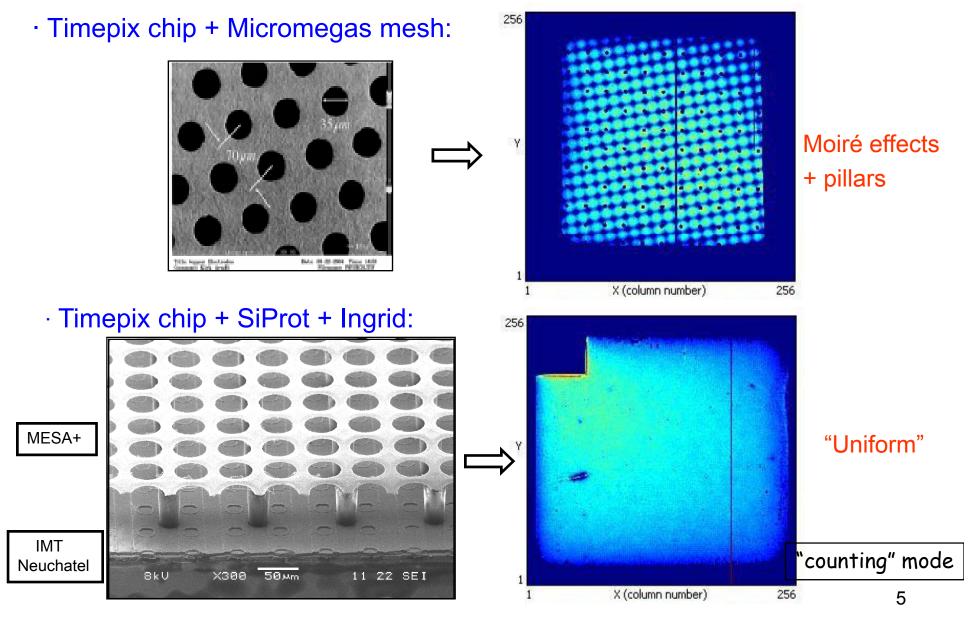
Available for use in detectors since Nov. 2006

## Timepix in gaseous detectors

- With Micromegas grid or GEM stacks
- Wafer postprocessing:
  - Integrated grid (Ingrid)
  - Enlarged pixels (with GEMs @ Freiburg)
- Discharge protection:

high-resistive (~10<sup>11</sup>)  $\Omega$ -cm amorphous Si layer (20  $\mu$ m thick) on top of CMOS chip (later maybe also high-resistive grid)

## Full post-processing of a TimePix

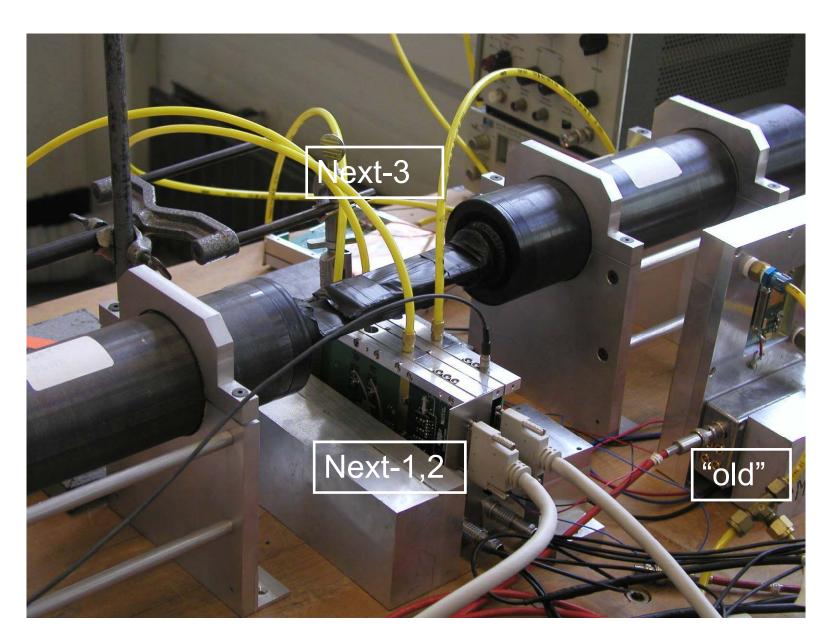


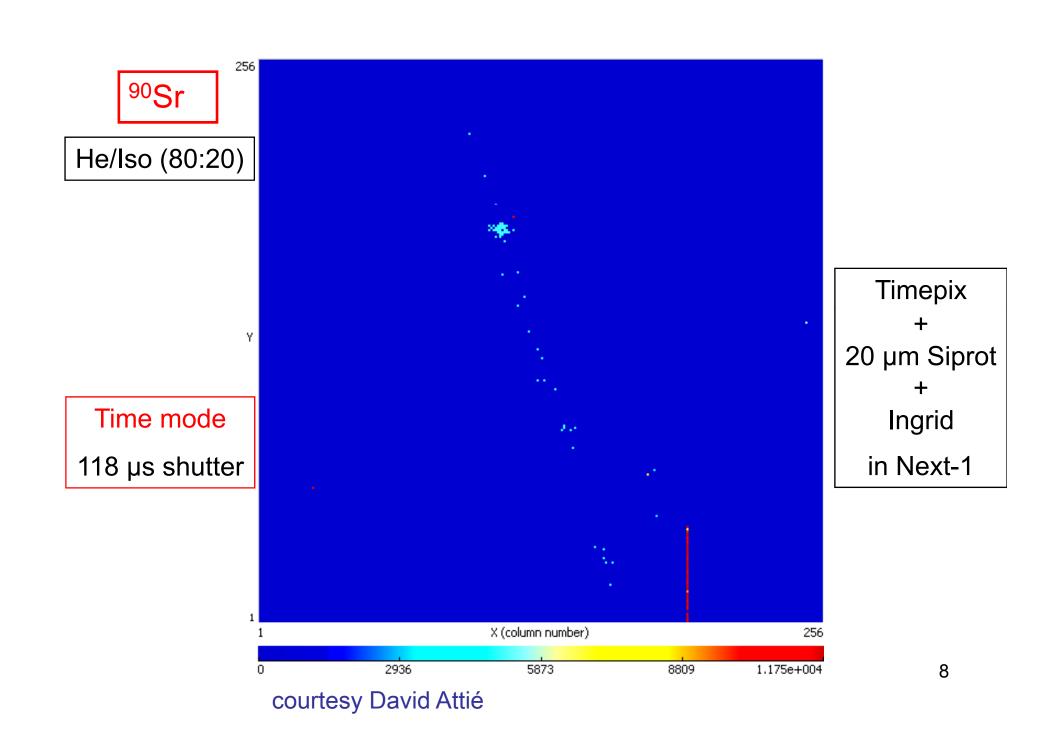
## "lifetime" of Medipix2/Timepix chips

"naked" Medipix chips:
 up to few hours; sometimes very short!
 (both in He and in Ar mixtures)

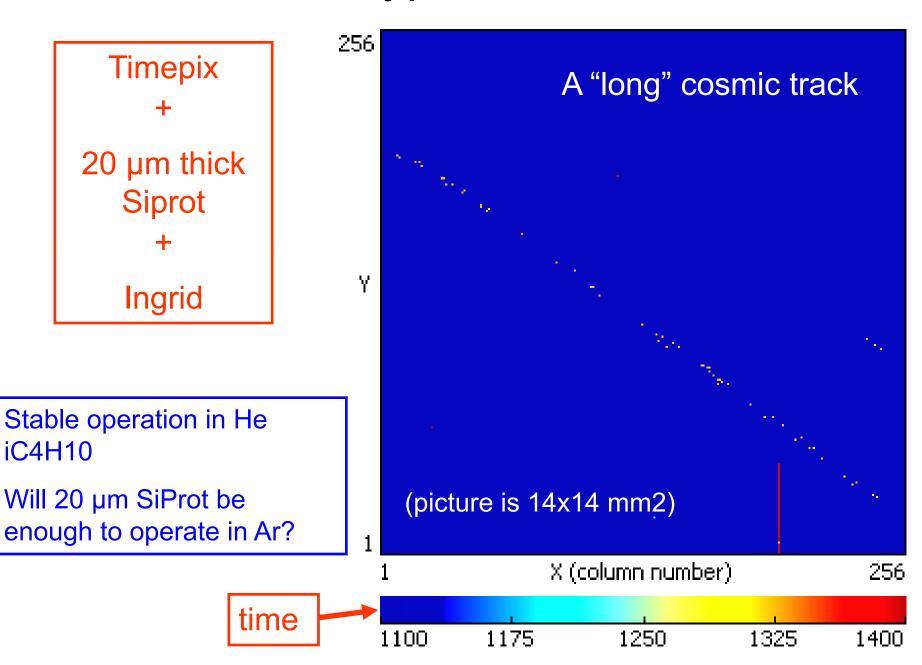
- With 4 μm amorphous Si:
  - in He/isobutane (80/20): > 3 months
  - In Ar/isobutane (80/20): ~ 1 day!
- With 20 μm protection layer ???

#### NIKHEF setup (> 22 Aug. 2007)

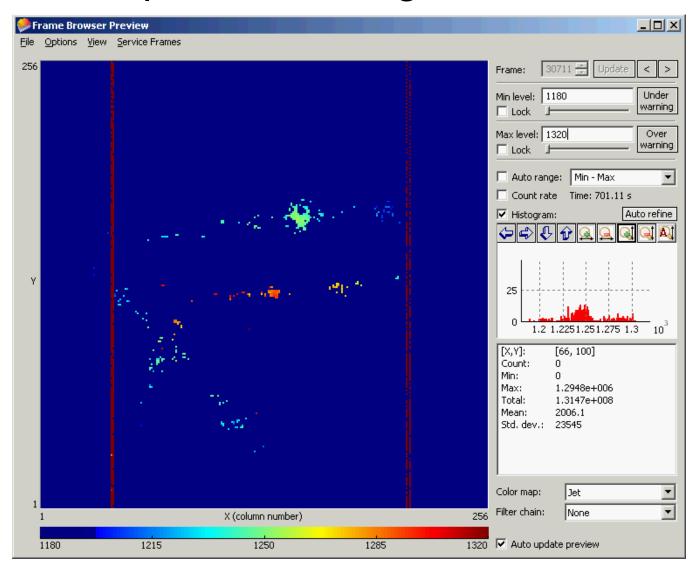




### The "typical" track



#### Stable operation in Argon too!



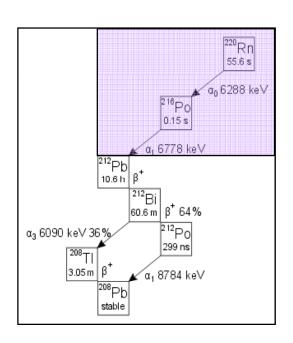
After 2 weeks of cosmic event recording, it was time for a definitive assessment whether 20 µm SiProt is enough to protect against discharges...

Time mode

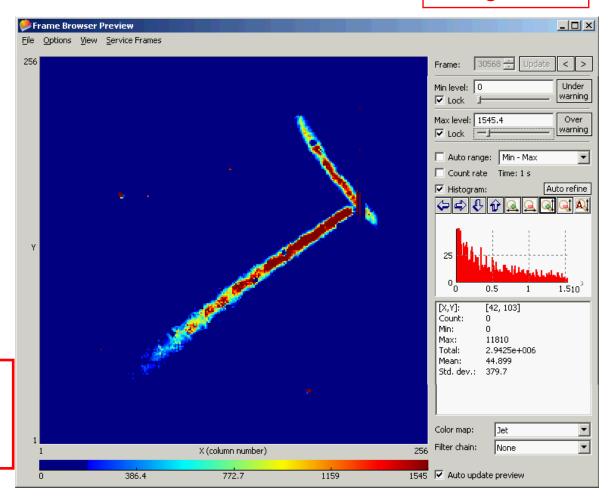
#### Final assessment: spark-proofness

- Provoke discharges by introducing small amount of Thorium in the Ar gas
  - Thorium decays to Radon 222 which emits 2 alphas of 6.3 & 6.8 MeV
  - Depose on average 2.5.10<sup>5</sup> & 2.7.10<sup>5</sup> e- in Ar/iC<sub>4</sub>H<sub>10</sub> 80/20 at -420 V on the grid, likely to trigger discharges

Charge mode



During ~3 days, some 5.10<sup>4</sup> alpha events recorded in 1% of which ...



### ... discharges are observed!

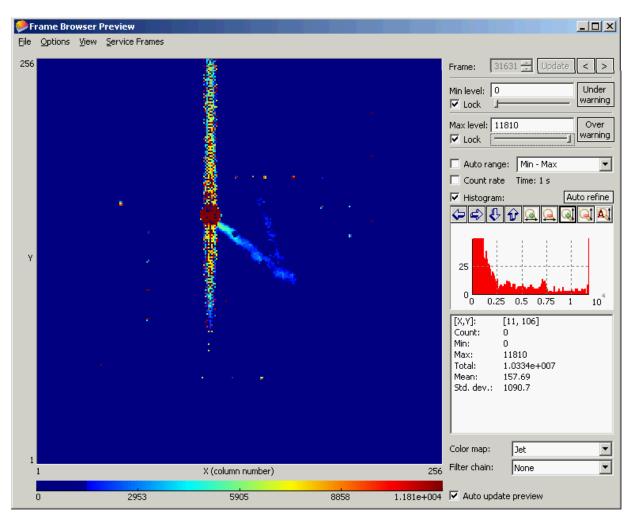
For the 1<sup>st</sup> time: image of discharges are being recorded

Round-shaped pattern of some 100 overflow pixels

Perturbations in the concerned column pixels

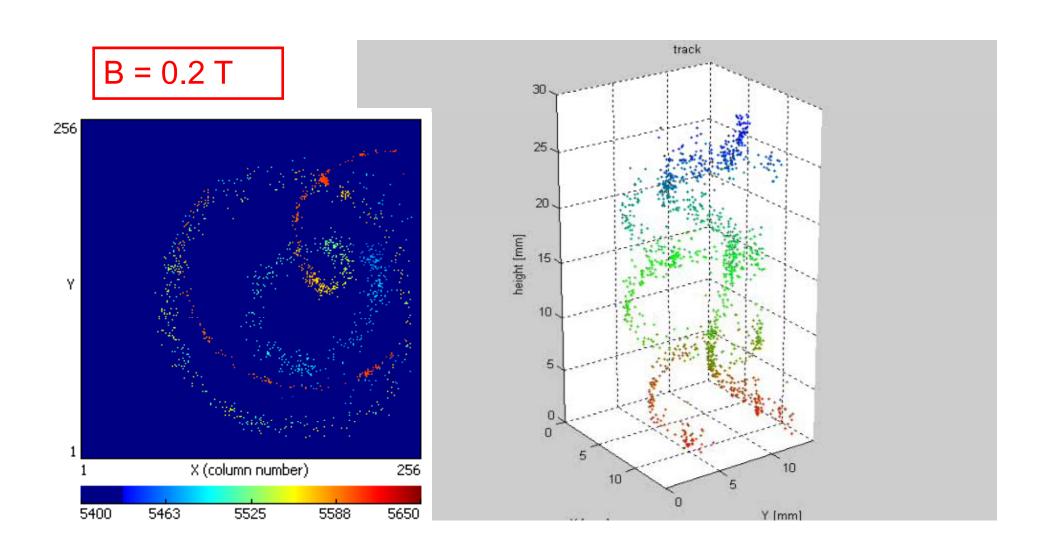
- Threshold?
- Power?

Chip keeps working!!



# Sofar with 20 µm no more Timepix chip damaged by discharges

### A 5 cm<sup>3</sup> TPC (two electron tracks from <sup>90</sup>Sr source)



## Pixel systems sofar....

- Timepix (also Medipix2) with triple-GEMs (Freiburg, Bonn)
- Timepix (also Medipix2) with single Micromegas (NIKHEF, Saclay)

#### Now:

- Timepix + amorphous Si (highly resistive) + integrated grid (Ingrid) (NIKHEF), soon also Saclay Will compare performance different thickness of protection layer: 0, 5, 10, 15 and 20  $\mu$ m
- larger drift lengths, up to 100 mm

- Sofar single-chip systems used
- Soon (Eudet deliverable) small multi-chip systems:
  - Bonn: two 4-chip boards → on endplate module
  - Saclay: one 8-chip board → on endplate module
  - NIKHEF: 4-chip board, fitting single-chip detector mechanics and drifter (could become endplate module)
- Later (~3/2009): aim for a 64-chip system (NIKHEF; may be too ambitious; bottleneck could be production of sufficient # Ingrids)

## Summary

- A lot of progress made in last 'year'; not mentioned many details on track resolution studies and on signal development
- Part of the technology is ready:
  - Very good energy resolution for Ingrid devices
  - Ion backflow at the few per-mil level at high field ratio
- Discharge protection seems working for Ingrid (and Micromegas) devices
- Robust operation with GEM devices (without protection)

#### Next:

Build larger multi-chip detector systems with fast readout

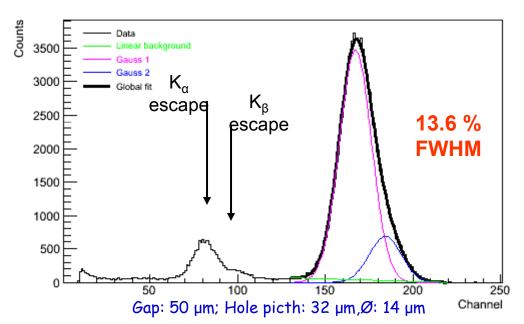
## Backup slides

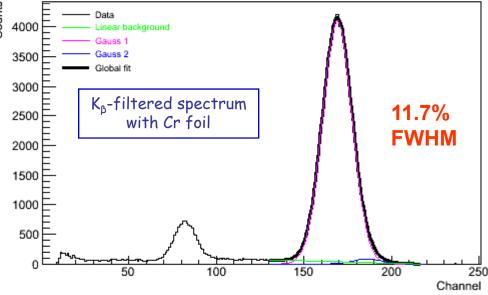
#### Status of Timepix usage at NIKHEF

TPX operated 13 dec. B05 with 3 µm SiProt & Micromegas in He 20% iC4H10 1 month in He iC4H10 Switch to Ar 20% iC4H10, chip died after 2 days 24 jan. 1st fully post processed MPX 20 mar. MediPix2 with 3 µm SiProt & InGrid operated 4 days in He C08 with 3 µm SiProt & Micromegas 17 apr. TPX & guard electrode (G.E.) in He operated 3 Stop C08 after 3 months of continuous operation in He 25 jul. months in He iC4H10 E09 with 20 µm SiProt & InGrid placed 1st fully post in NEXT-1 chamber in He A06 with 20 µm SiProt & Micromegas placed 22 aug. in NEXT-2 chamber in He Flush NEXT-2 (A06) with Ar, stable operation for >40 days! 04 sep. TPX Flush NEXT-1 (E09) with Ar, same nice results 23 sep. operated in Ar iC4H10 26 sep. Introduce Thorium in NEXT-2 (A06), provoke discharges Recording alpha's tracks & even more... 19 ALL STILL WORKING !!

#### New Ingrid developments and results

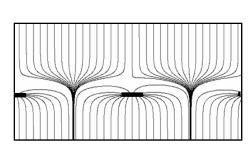
- Process improvement: grids much flatter
  - Extremely good energy resolution:
     13.6 % FWHM with <sup>55</sup>Fe in P10
  - Removal of  $K_{\beta}$  6.5 keV line: 11.7 % @ 5.9 keV in P10
- New wafer masks: hole pitches down to 20 µm with various diameters and gaps
  - Investigate Micromegas geometry
  - Test of the ion backflow theory
- Until now: 1 µm thin Al but can now be increased to 5 µm by electrolysis
   Expect less damaged from sparks

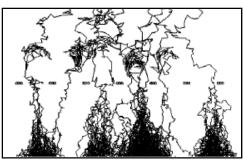


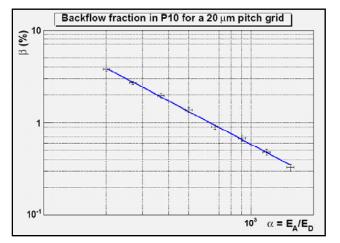


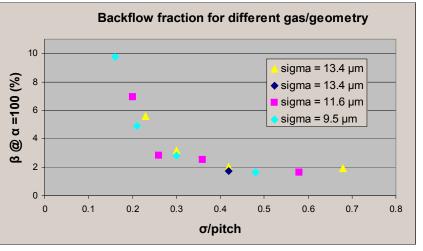
## InGrid ion backflow measurements

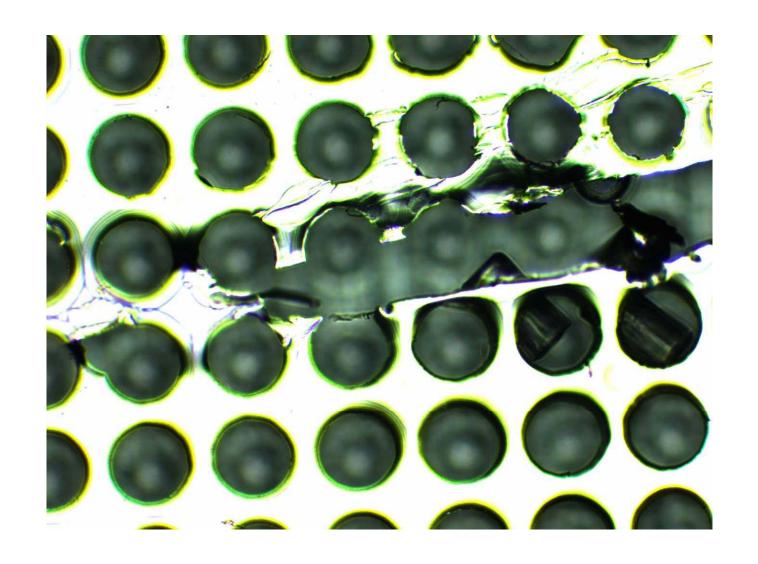
- Phenomenon depends on:
  - Avalanche charge distribution
  - Funnel size
- therefore on the gas and grid geometry
  - Q density in the funnel decreases with the avalanche transverse diffusion
  - Funnel size decreases with the field ratio and hole pitch
- Backflow fraction reaches a (minimum) plateau
  - Occurs when ions backflow through neighboring holes
  - Simulation predicts this to occur at  $\sigma/p = 0.5$











A "scratch" occurred during production Ingrid; Loose parts removed. Ingrid working!

# Measurement of discharge "spectrum" (signal from Ingrid recorded on digital scope)

